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/ Ruth Montalvo Date: 06/17/05

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney's Docket No.: GK-ZEI-3278/500343.20298
 U.S. Application No.:
 International Application No.: PCT/EP2003/0013476
 International Filing Date: NOVEMBER 29, 2003 29 NOVEMBER 2003
 Priority Date Claimed: DECEMBER 19, 2002 19 DECEMBER 2002
 Title of Invention: METHOD AND ARRANGEMENT FOR OPTICAL EXAMINATION OR
 PROCESSING OF A SAMPLE
 Applicant(s) for (DO/EO/US): Ralf WOLLESCHENSKY and Michael KEMPE

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 Alexandria, VA 22313-450

INFORMATION DISCLOSURE STATEMENT

SIR:

Applicant herewith submits together with the simultaneously filed National Phase application of PCT/EP2003/0013476, a copy of the International Search Report (PCT/ISA/210) dated March 18, 2004, and German Examination Report (102 59 443.0) dated September 2, 2003, citing the following references:

	Document Number	Date	Name and/or Country	English Abstract / US Equivalent
AA	5,583,342	12/10/1996	Ichie	
AB	5,648,866	07/15/1997	Trebino, et al.	
AL	1439519	11/23/1988	Soviet Union	
AM	196 22 359	12/11/1997	Germany	US 6,178,041
AN	197 44 302	04/15/1999	Germany	US 5,995,281
AO	198 27 139	04/15/1999	Germany	US 6,269,206
AP	198 29 981	01/05/2000	Germany	US 6,462,345
AQ	198 35 072	02/10/2000	Germany	US 2004/0174593
AR	199 30 532	01/11/2001	Germany	US 2005/0017160
AS	1 143 282	10/10/2001	European	US 2001/0043403

Accompanying this Information Disclosure Statement and form PTO-1449 are copies of the foreign documents including English Abstracts and first page only of documents
Documents **AN**, **A0-APA** and **AR** are mentioned on pages 1, 8 and 10 of the substitute specification.

The USPTO waived the requirement under 37 C.F.R. §1.98(a)(2)(i) for submitting copies of US patents and US patent application publications in all U.S. applications filed after June 30, 2003. First page only of documents.

This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,



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Enclosures:

Search Reports (PCT/ISA/210);
German Examination Report
PTO-1449;
8 Foreign documents
~~English Abstracts~~
6 US first page(s)
3 US publication(s)

LIST OF PRIOR ART CITED BY APPLICANT
(Filed on June 17, 2005)

Docket No. **GK-ZEI-3278/500343.20298**Applicant(s): **Ralf WOLLESCHENSKY and Michael KEMPE**

Application No. (Int'l Appln No. PCT/EP2003/013476 29NOV03) Group:

Filed: Concurrently herewith – June 17, 2005

Examiner:

U.S. PATENT DOCUMENTS

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
.	AA	5,583,342	12/10/1996	Ichie			
	AB	5,648,866	07/15/1997	Trebino, et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	CLASS	Sub-Class	Translation YES	NO
	AL	1439519	11/23/1988	Soviet Union				<input checked="" type="checkbox"/> X
	AM	196 22 359	12/11/1997	Germany				US 6,178,041
	AN	197 44 302	04/15/1999	Germany				US 5,995,281
	AO	198 27 139	04/15/1999	Germany				US 6,269,206
	AP	198 29 981	01/05/2000	Germany				US 6,462,345
	AQ	198 35 072	02/10/2000	Germany				US 2004/0174593
	AR	199 30 532	01/11/2001	Germany				US 2005/0017160
	AS	1 143 282	10/10/2001	European				US 2001/0043403
	AT							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AX	
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AZ	

Examiner:

Date:

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.